



# Improving Yields and Quality: Two Case Studies: Graping and the Head-on-Pillow defect

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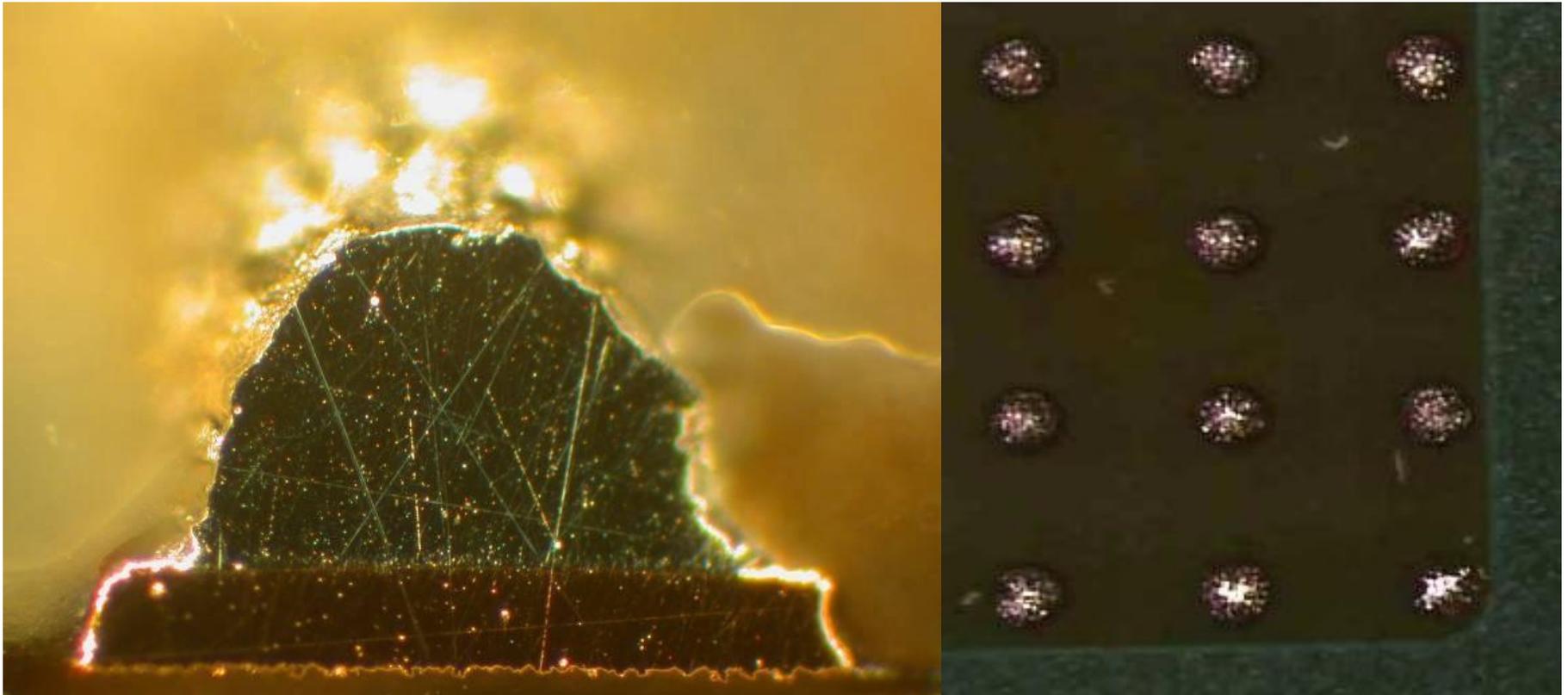
Professor, Dartmouth College



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ENGINEERING  
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# Graping



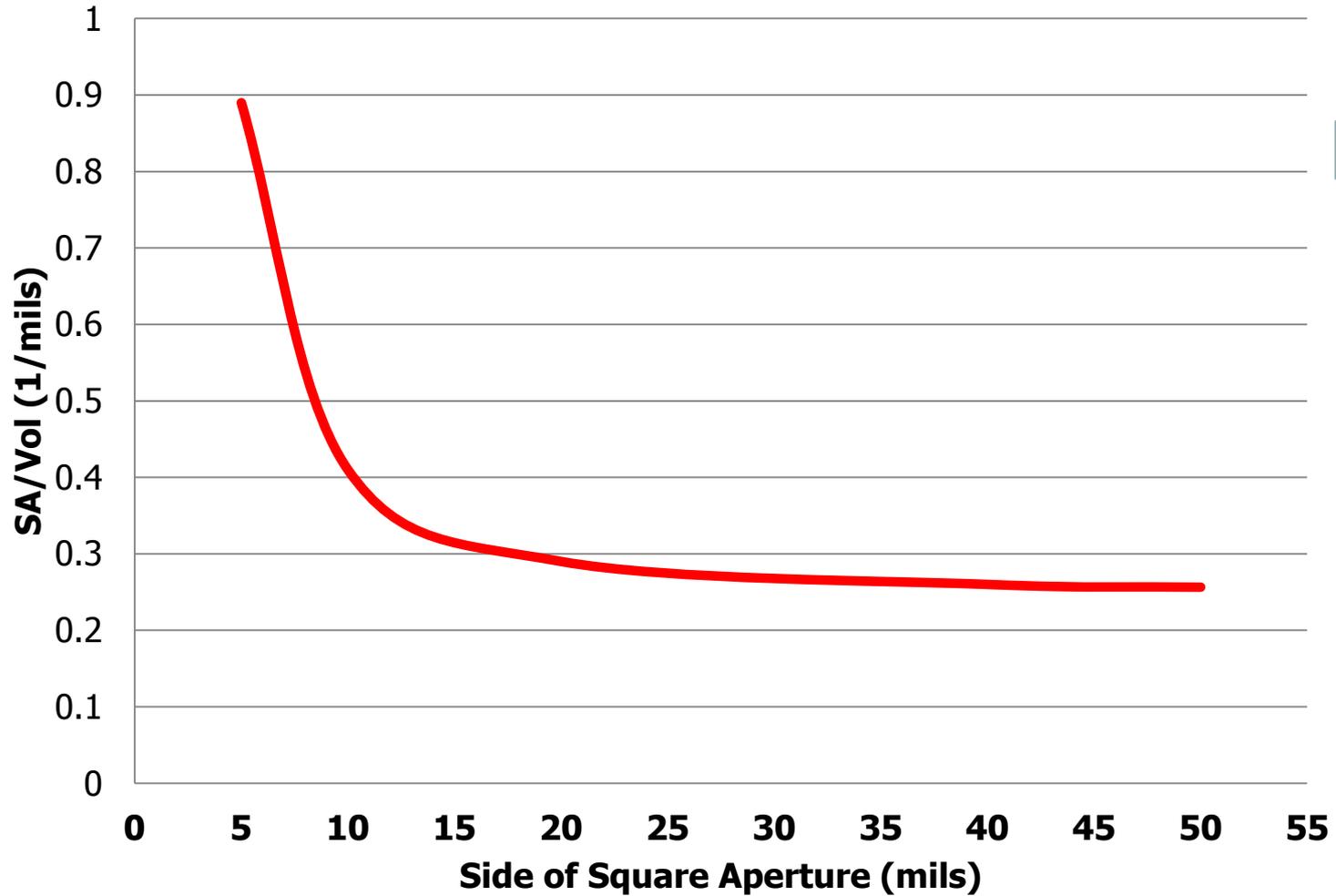
Slide #2

## Graping

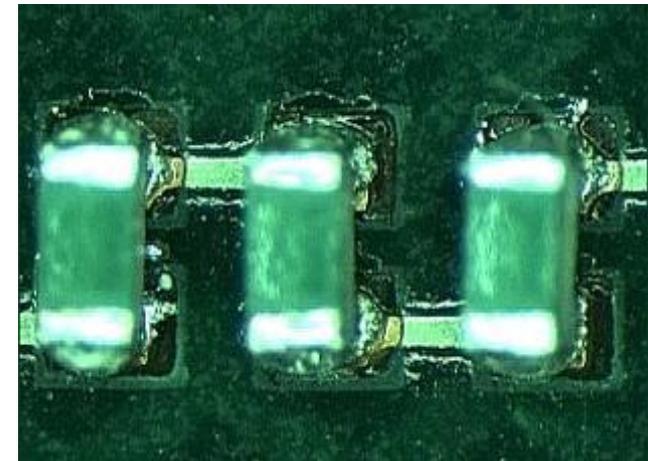
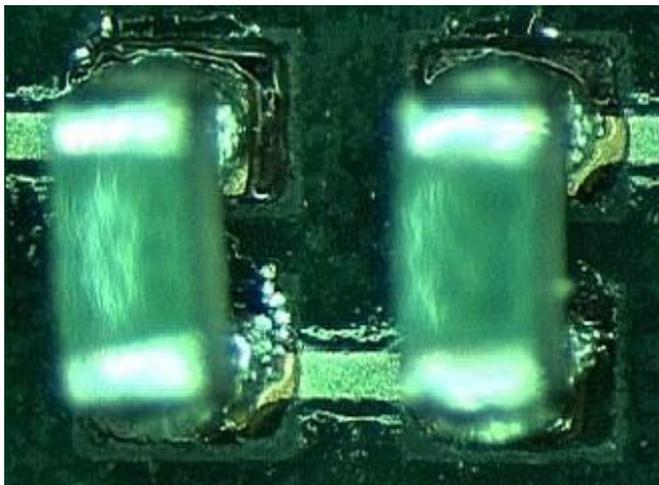
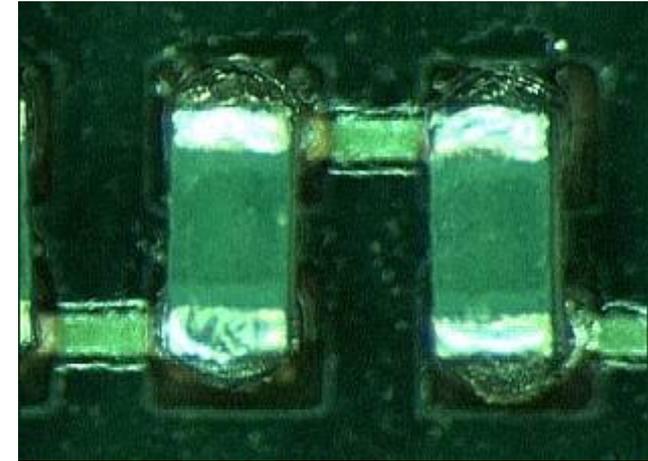
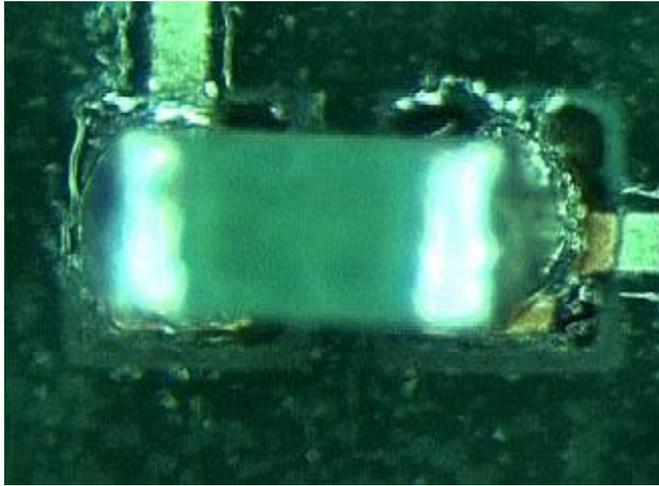
- Miniturization of electronics has given us 01005 passives and 0.4 to 0.3 mm pitch packages
- The resulting smaller solder paste deposits = surface powder oxidation
- Higher process temperatures (i.e. 227C vs 217C) may exacerbate graping (and tombstoning)
- Dopants such as P and Ge may help (control oxidation)



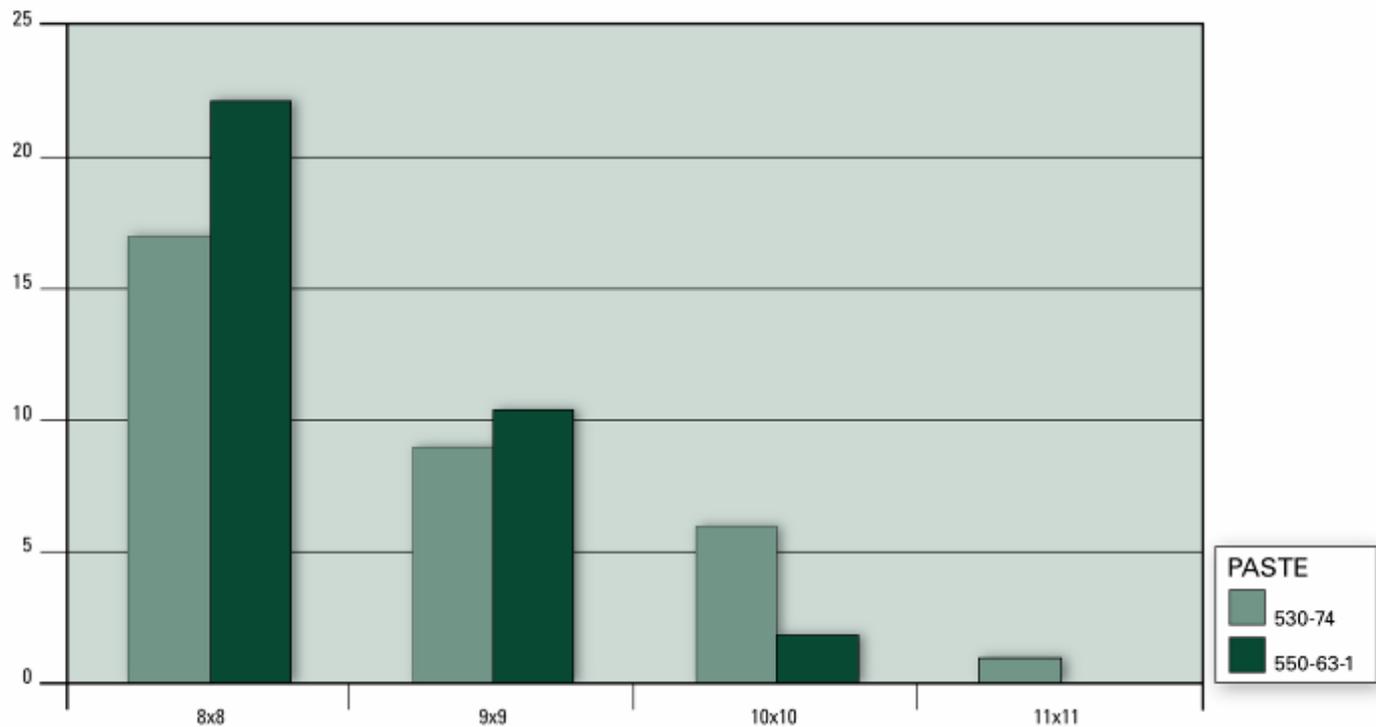
### Surface Area/Volume (4 mil stencil)



# Small Deposit Coalescence Challenge



# Graping vs. Aperture Size

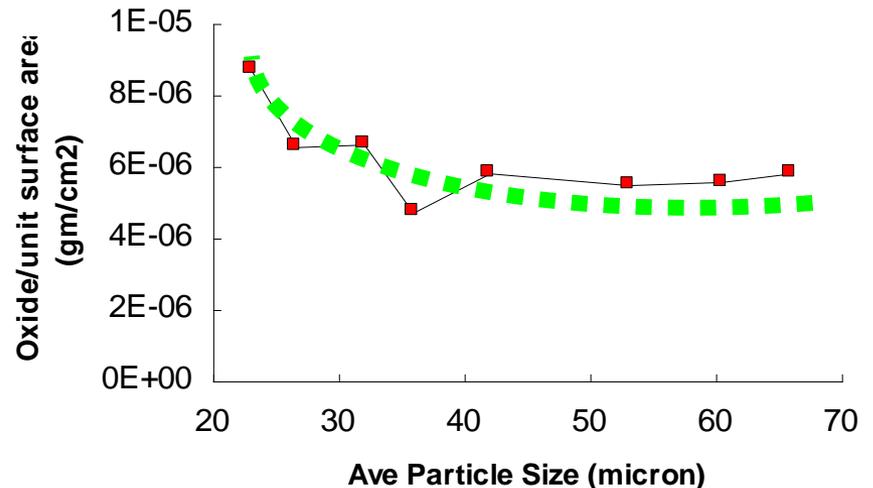


# Smaller Apertures Require Finer Paste Particle Sizes

<i><b>Powder Size</b></i>		
	<i><b>Diameter Range</b></i>	
<i><b>TYPE</b></i>	<i><b>microns</b></i>	
<b>3</b>	<b>25</b>	<b>45</b>
<b>4</b>	<b>20</b>	<b>38</b>
<b>5</b>	<b>15</b>	<b>25</b>
<b>6</b>	<b>5</b>	<b>15</b>

# Oxidation Challenge

- Finer powder needed for finer pitch
- The higher surface area per unit volume aggravate oxidation issue
- Oxide thickness become higher for very fine powder due to high curvature thus high energy state
- Anti-oxidation dopants such as **P**, **Ge**, desired for alloying



Oxide layer thickness increases for fine powder

(Indium)

# Microalloying

A Nickel Addition was found to be most effective

Sn-0.7Cu



Sn-0.7Cu+0.06Ni



# Microalloying

The Ge acts as an antioxidant and surface active agent



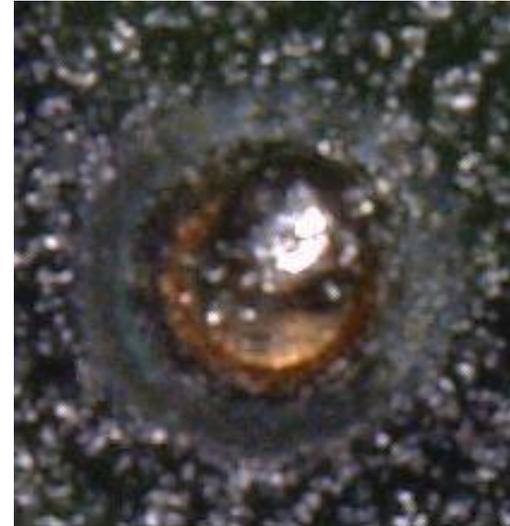
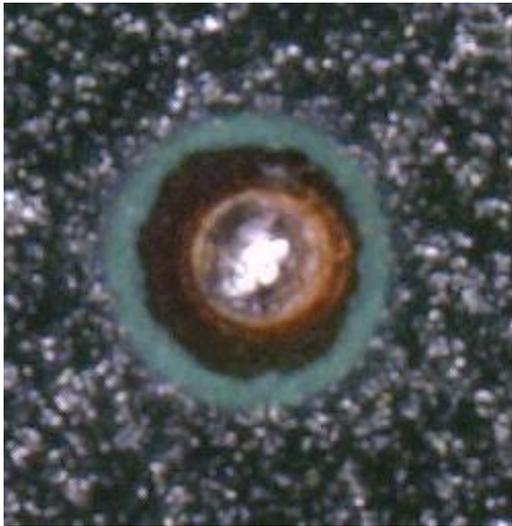
Sn-0.7Cu-0.05Ni

15 minute  
Ramp to 340°C  
30 minute cool



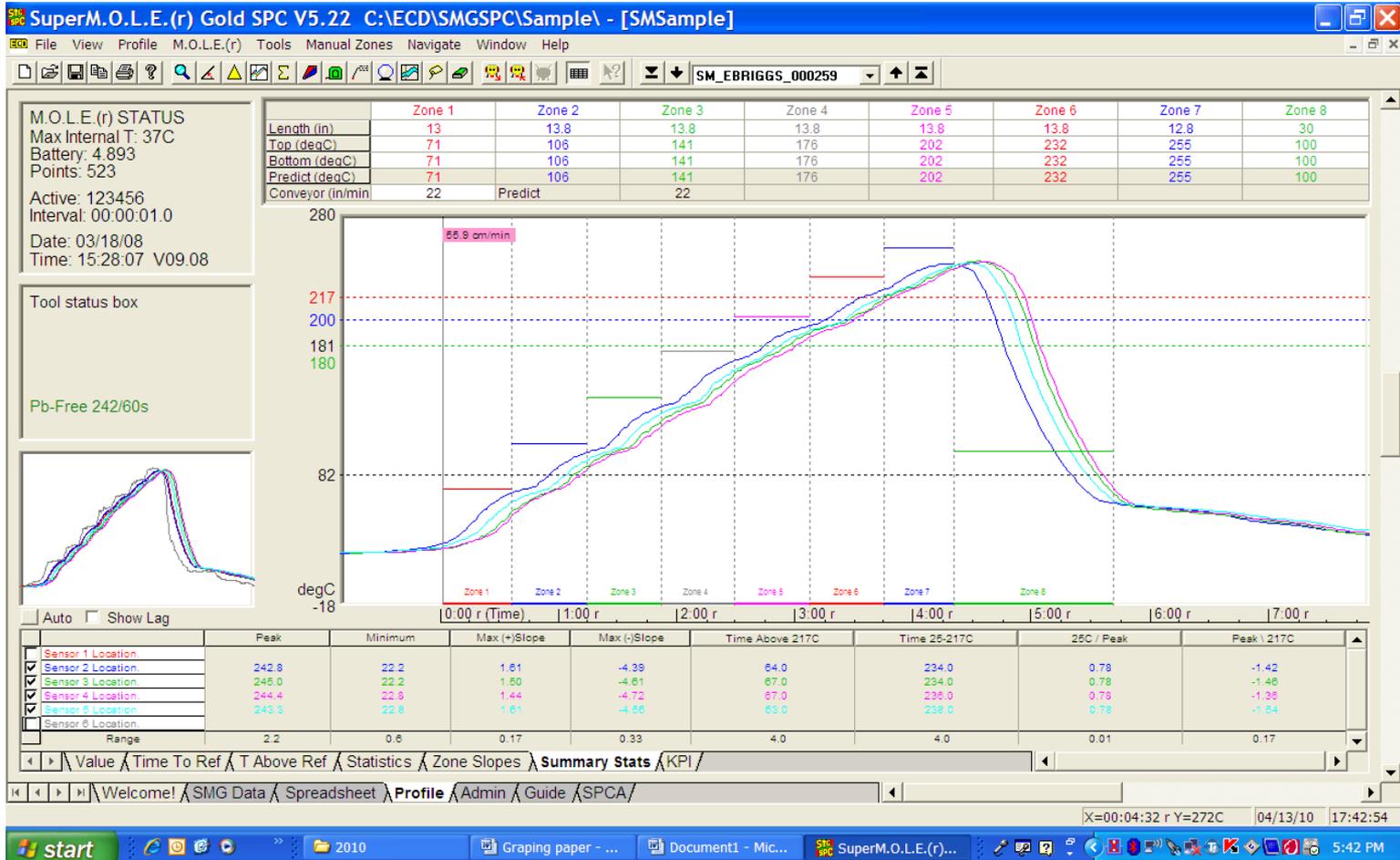
Sn-0.7Cu-0.05Ni+Ge

# Particle Size Effect on Reflow Result

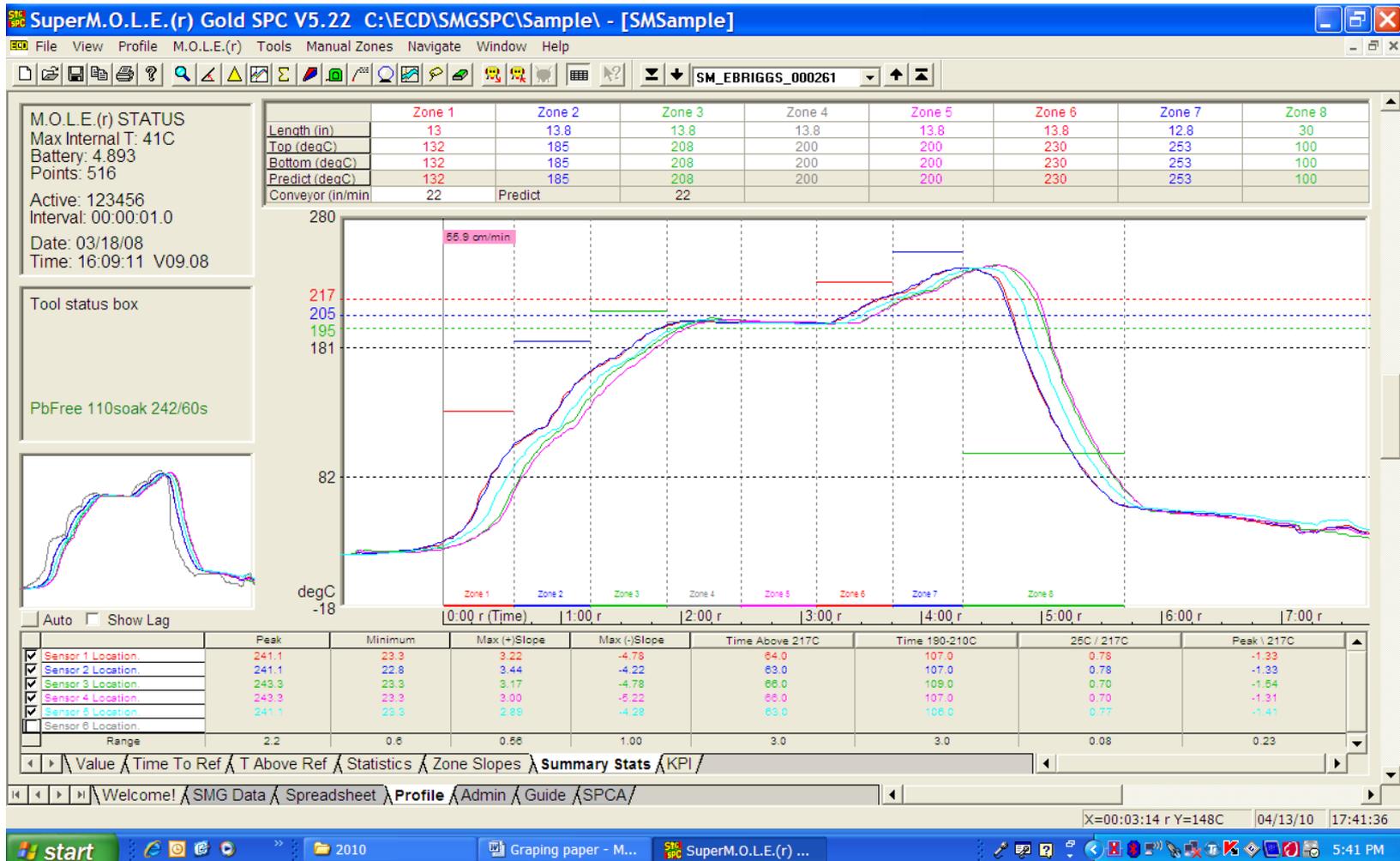


**Typical results:** Type 3 (left) vs. Type 6 (right) using the same no-clean flux chemistry and reflow profile (RTP).

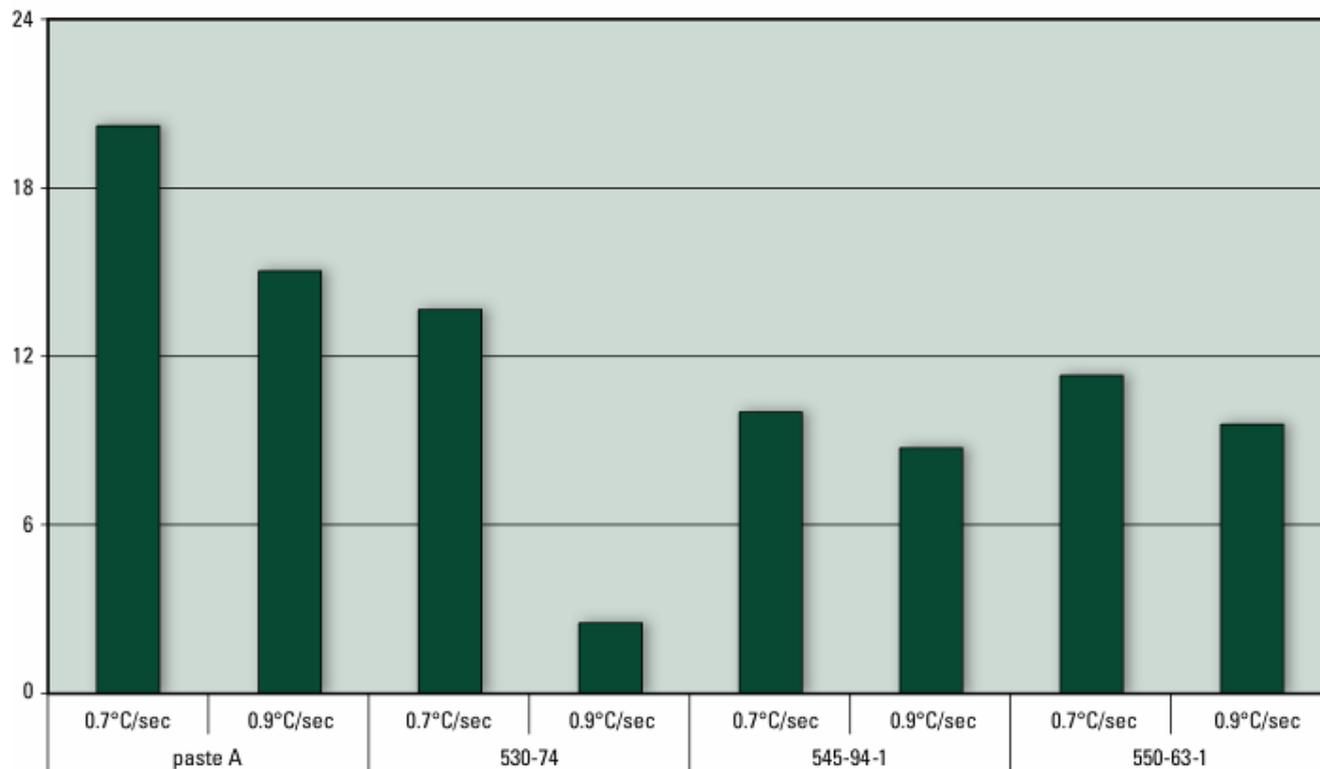
# Ramp to Peak Profile



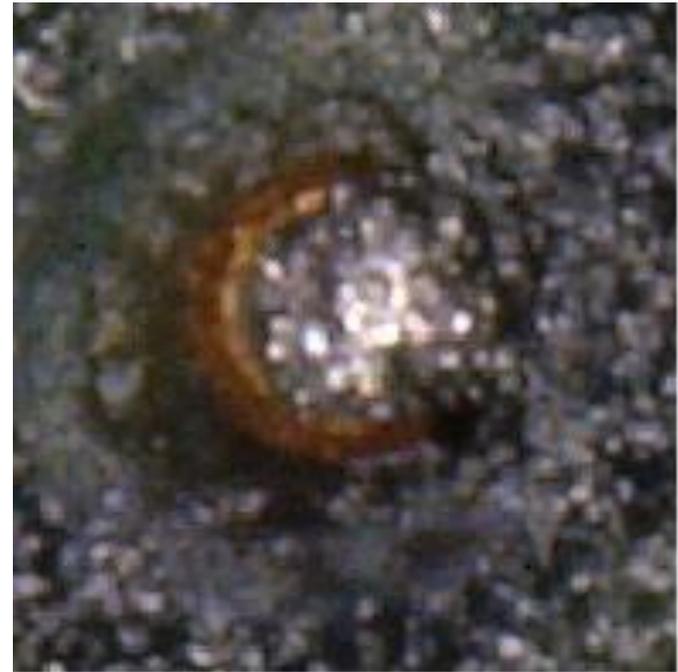
# Soak Profile



# Profile Optimization

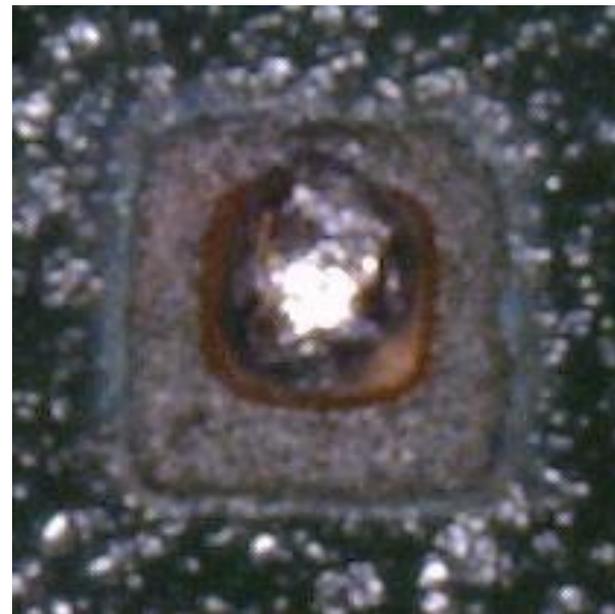


# Ramp-to-Peak (RTP) vs. Soak



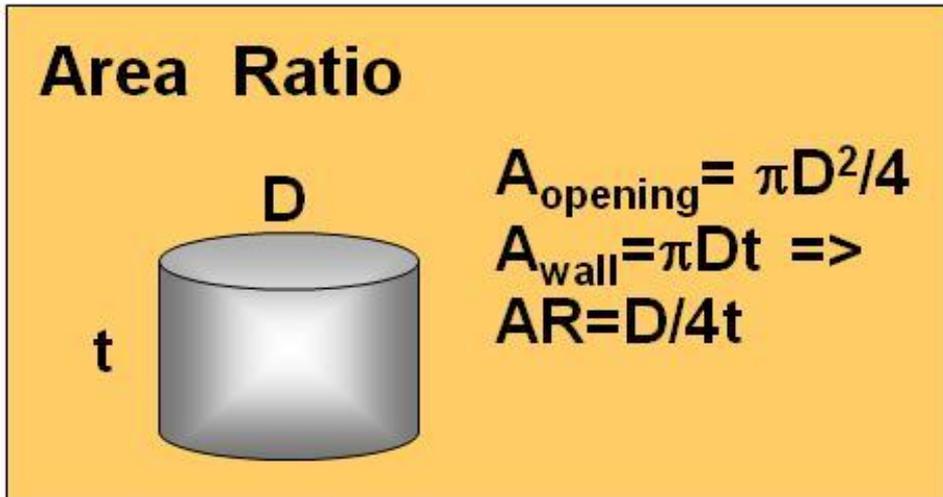
**Typical results:** RTP profile (left), soak profile (right) using the same Type 6 powder size and flux chemistry (no-clean),

## Round Aperture vs. Square Aperture



**Typical results: Circular aperture/pad (left), square aperture/pad (right) using the same Type 3 powder size, area ratio, flux chemistry (no-clean), and reflow profile (RTP).**

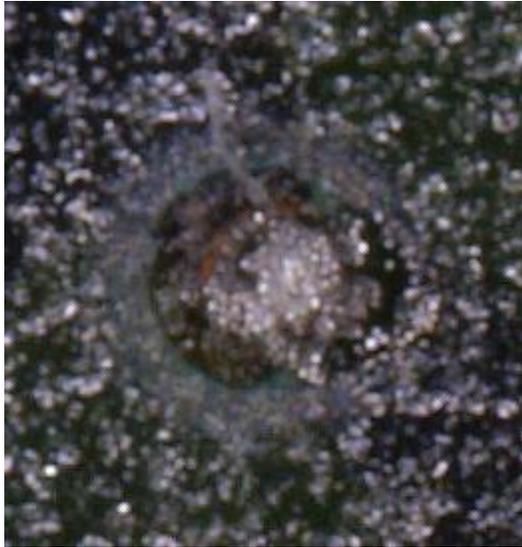
# Why the Difference?



- AR > 0.66 for good printing
- Some modern pastes can print <0.50
- Should be verified experimentally

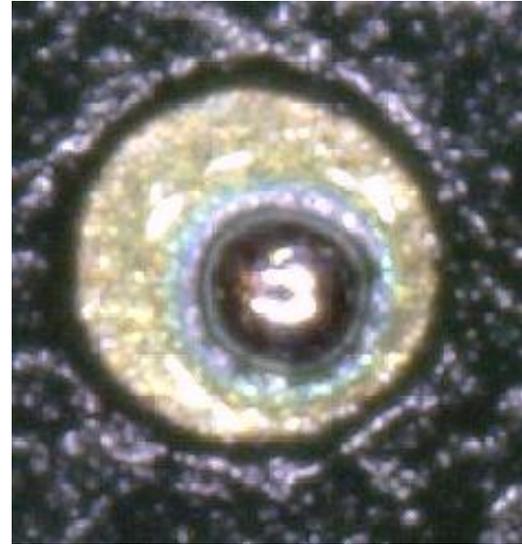
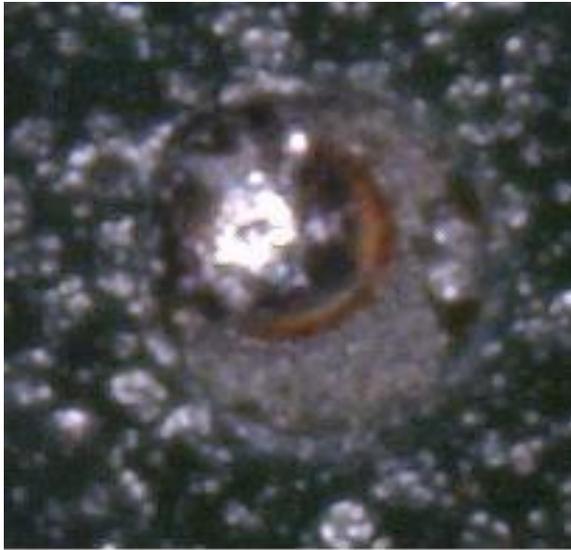
- AR for square:
  - $D^2/4Dt = D/4t$
- But area of circle =  $\pi D^2/4 = 0.785 D^2$
- $D^2$  for a square
  - >25% more volume
- Plus experiments show better transfer efficiency from square apertures
  - >40% more volume

# Water-Soluble vs. No-Clean



**Typical results:** Water-soluble (left) vs. no-clean (right) using the same Type 6 powder size and reflow profile (RTP).

# Solder Mask Defined is Better



**Typical results:** Non-solder mask defined pad (left), solder mask defined pad (right) using the same Type 6 powder size, flux chemistry (no-clean), and reflow profile (RTP).

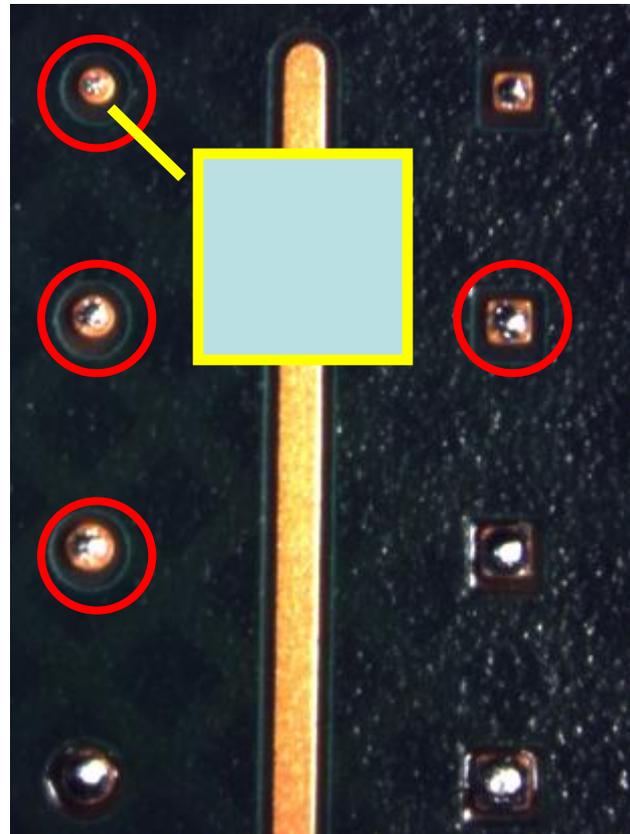
# Graping Paste "A" vs. Others

The pads in red circle showed graping symptom

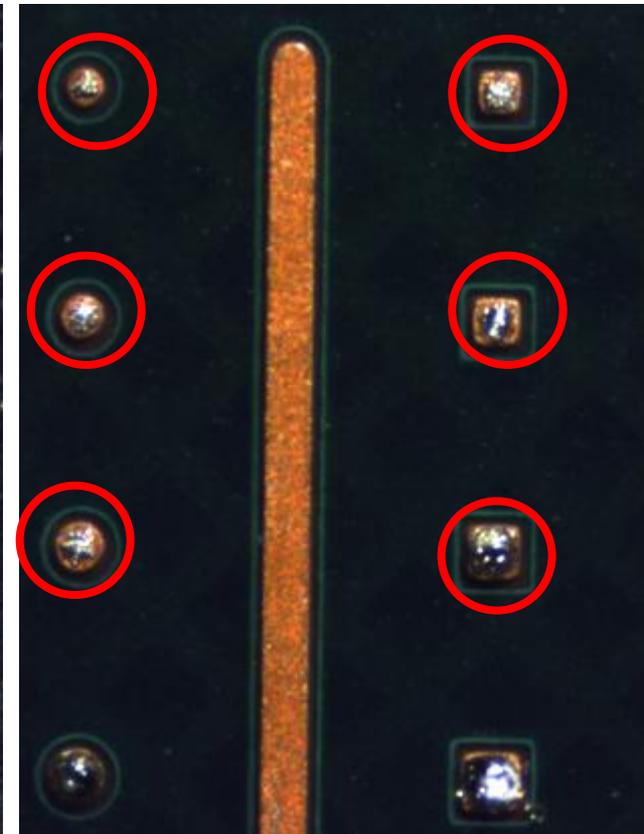
Paste A



S



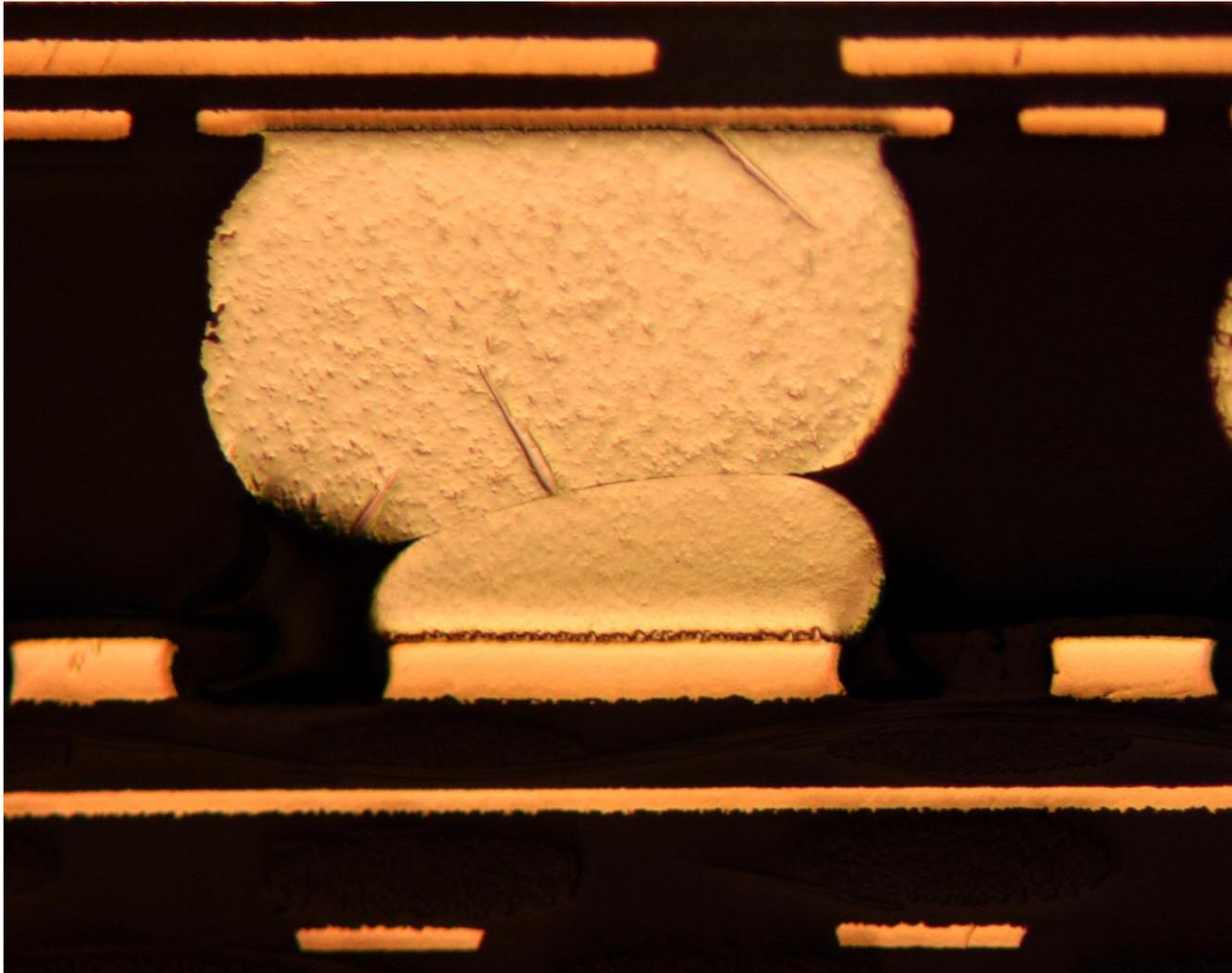
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# To Minimize Graping

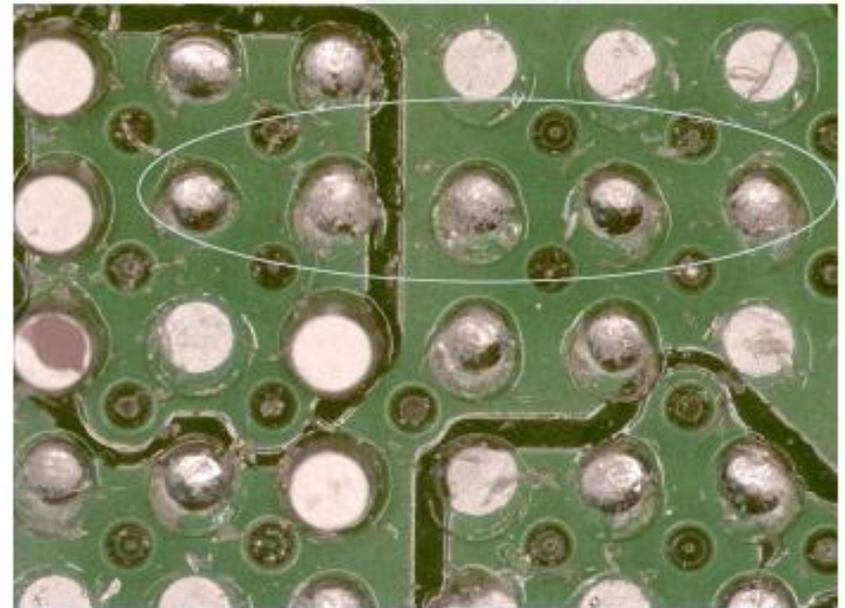
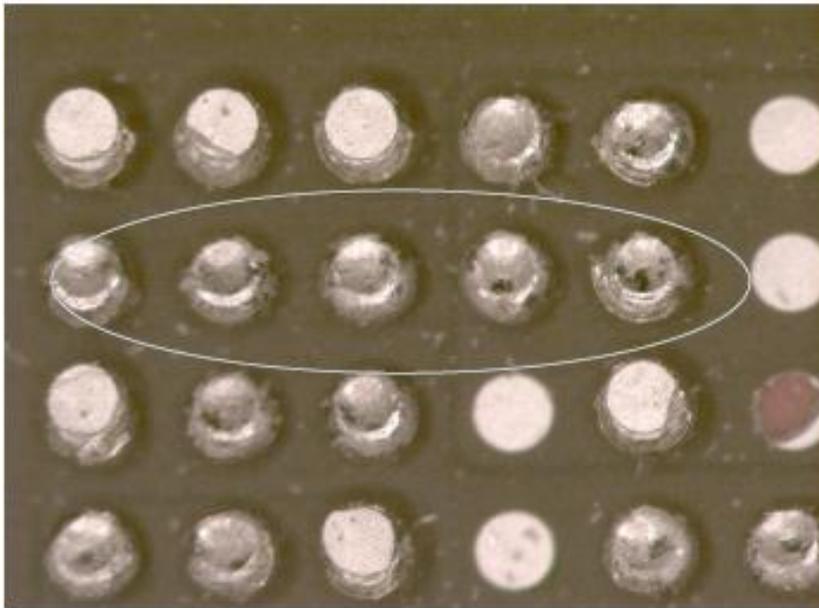
- Choose largest acceptable powder size
  - In most cases Type IV or courser
- Use a no clean paste
- Minimize time at high T
  - Ramp to peak
- Use square apertures, a little over size if possible to get the most amount of paste
- Use Solder Mask Defined Pads
- Choose a good paste

# Head on Pillow (HoP)

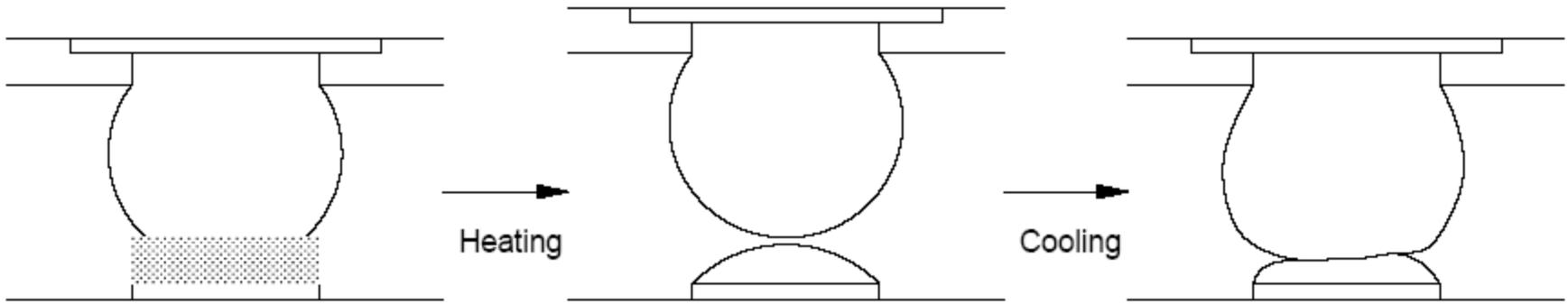


# Overview

- Why is it an issue?
  - Still passes ICT & function testing
  - Cause of field failures



# How HoP Happens

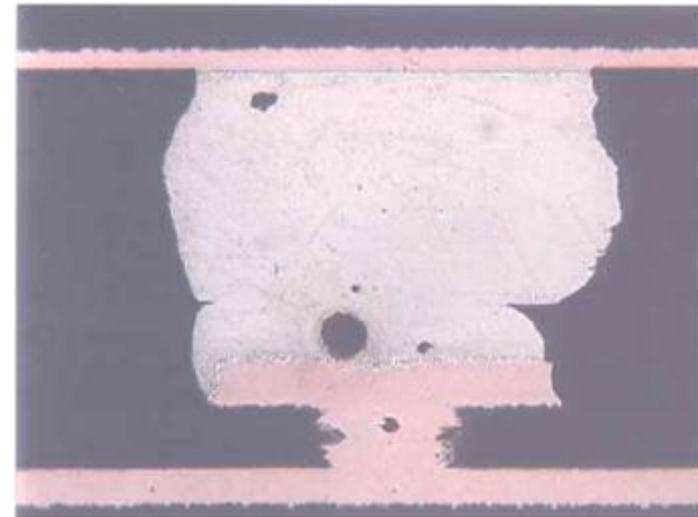
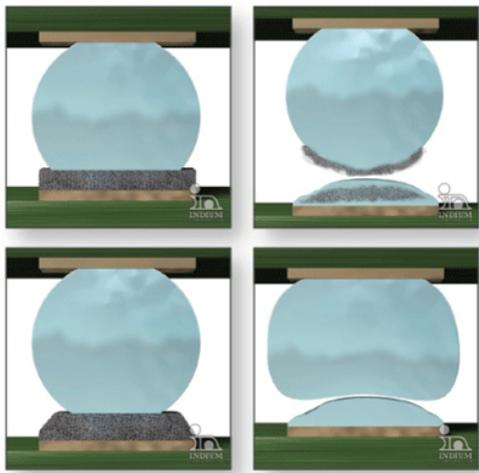


BGA placed on solder paste

Increased spacing due to warping.  
Both sides in liquid state.

Spacing closed down at cooling,  
contacting each other after solidification

## Problem:



# Types of HoP

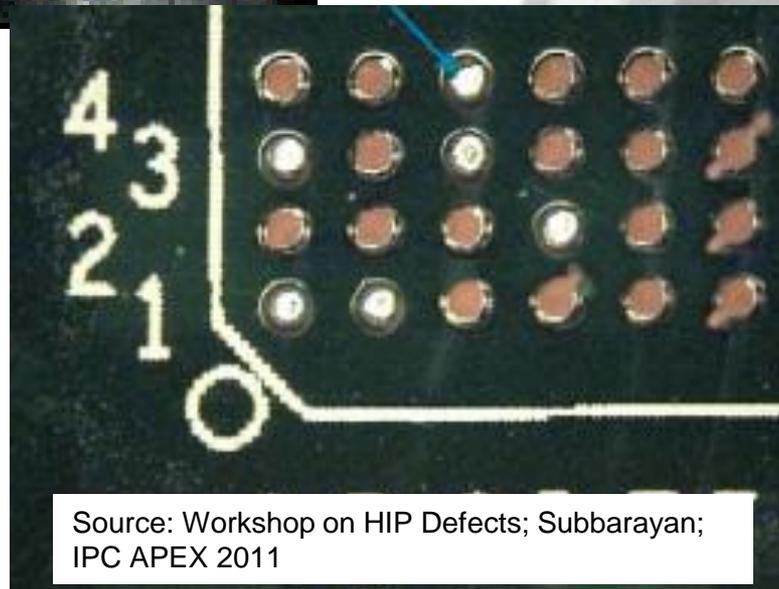
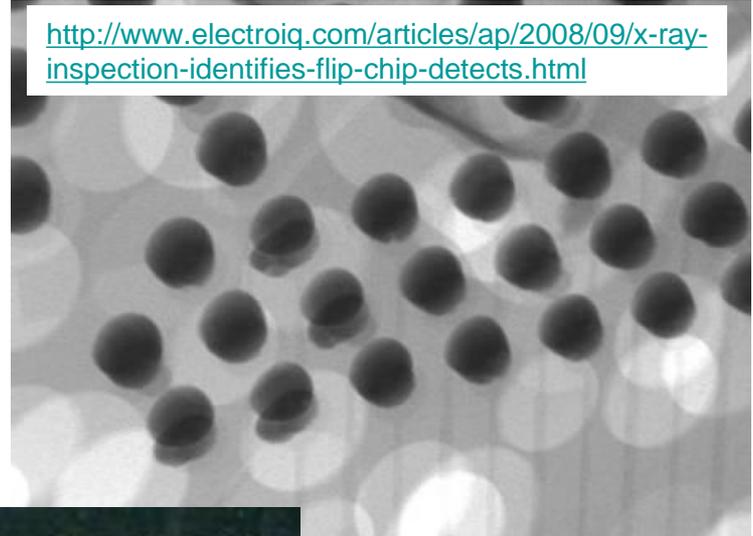
- Type 1: Excessive BGA Oxide or Contamination
  - The oxide film on solder ball is too thick for solder paste to break through to coalesce.
- Type 2: Excessive Warpage
  - Solder solidified already when the BGA ball is brought back in contact with solder dome on pad
- **Type 3: Warpage + Oxidation**
  - **Solder still in molten state when solder ball was brought in contact with solder dome on pad. However, the oxide film prevent the coalescence of two solder bodies.**

# Detecting HoP

Source: <http://ppsimanufacturing.wordpress.com/>



<http://www.electroiq.com/articles/ap/2008/09/x-ray-inspection-identifies-flip-chip-detects.html>



Source: Workshop on HIP Defects; Subbarayan;  
IPC APEX 2011

# Three Important HoP Trends

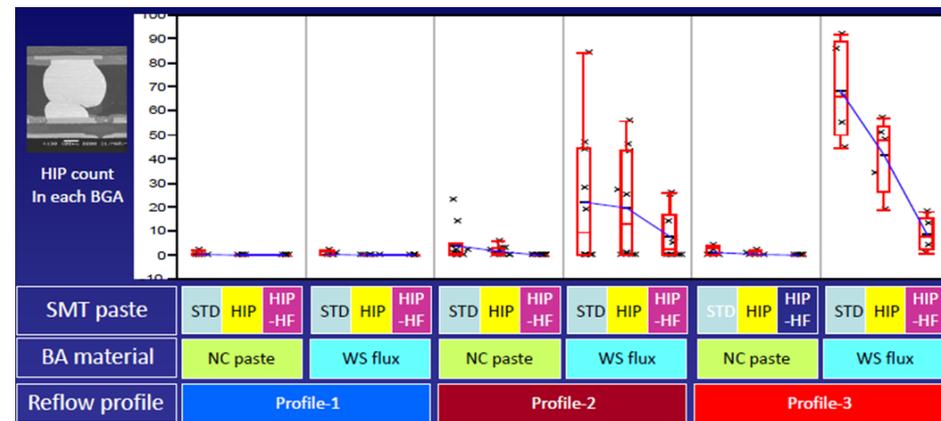
- Halogen-Free
  - Material Definition
  - Legislation
- Pb-Free and Mixed Alloys
  - Voiding and Reflow Temperatures
  - Drop Shock Resistance
  - Thermal Cycling
- Miniaturization (with #1 and #2 sprinkled in)
  - Printing
  - Graping
  - Head-in-Pillow

# Investigation: Components

- Component Warpage
- Coplanarity
- Sphere Oxidation
  - Uncontrolled manufacturing
  - FIFO
  - Packaging
  - Storage
- Cleaning process after ball-attach
  - Contaminants from solution
  - Incomplete cleaning
  - Hydroxide formation
- Ball Alloy (match w/ paste)

Part	Lot #	Max Warpage Temp'	Range (Microns)	Average (Microns)	Std Dev
1	a	Var'	80-100	91	6
1	b	250	73-90	82	7
1	c	220	73-90	83	8
1	d	180	47-90	73	16
1	e	240	61-107	78	17
1	f	250	65-76	69	4
1	g	250	63-82	70	7
2	a	250	96-106	101	4
2	b	250	101-114	107	6
2	c	250	85-91	89	3
2	d	250	79-92	84	6

Source: *Head-On-Pillow Defect – A Pain in the Neck or Head-On-Pillow BGA Solder Defect*; Oliphant et al; APEX 2010



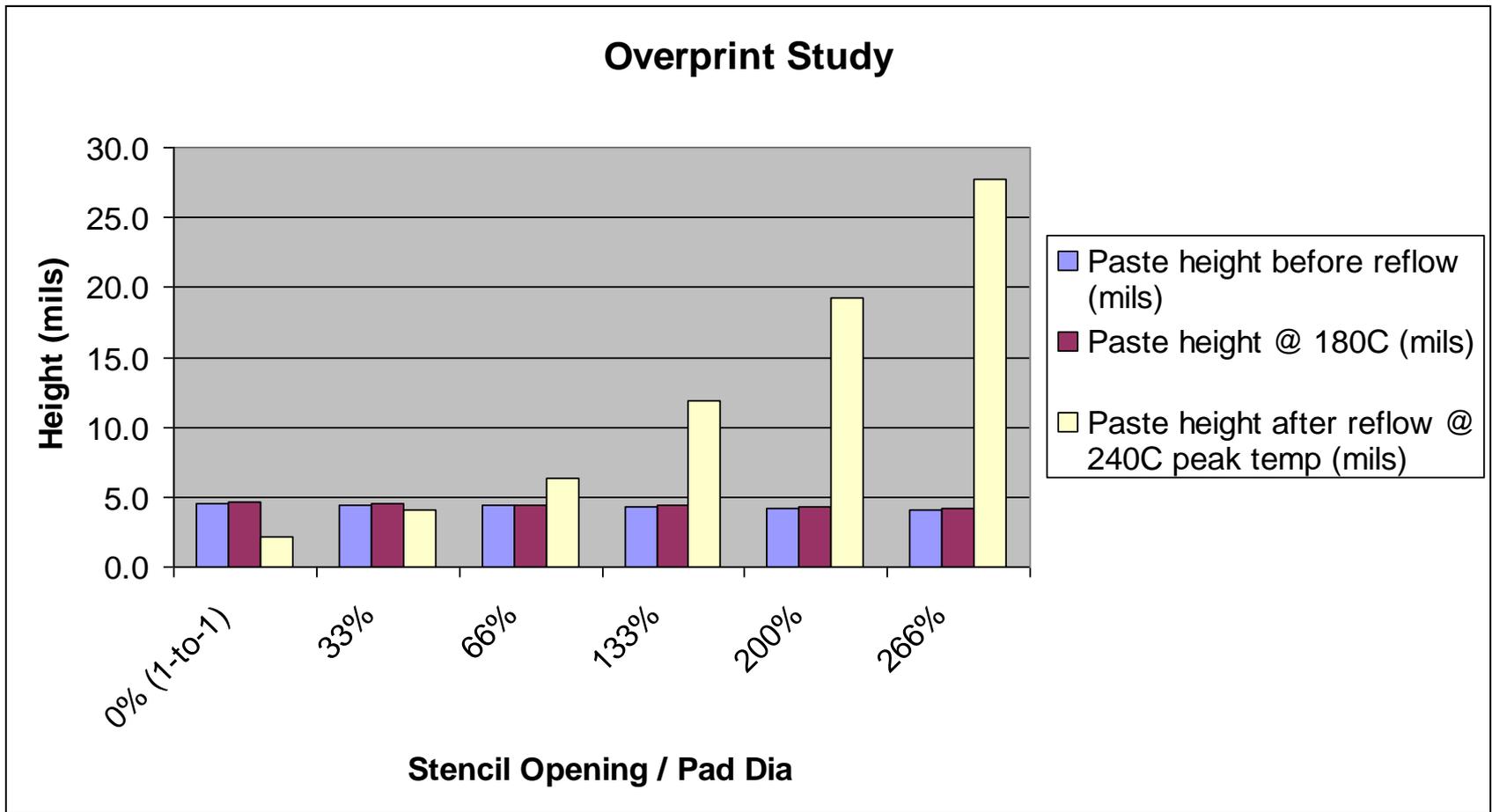
Source: *Head in Pillow: Are We Still Snoozing*; Shimanura et al; SMTAI 2010 Proceedings

# Investigation: Printing Process

- Setup
  - Poor registration
  - Improper board setup
  - Aperture area ratio
  - Stable board support and clamping system (vacuum)
  - Poor stencil design
- Materials
  - Transfer efficiency
  - Slump resistance



# Over Printing

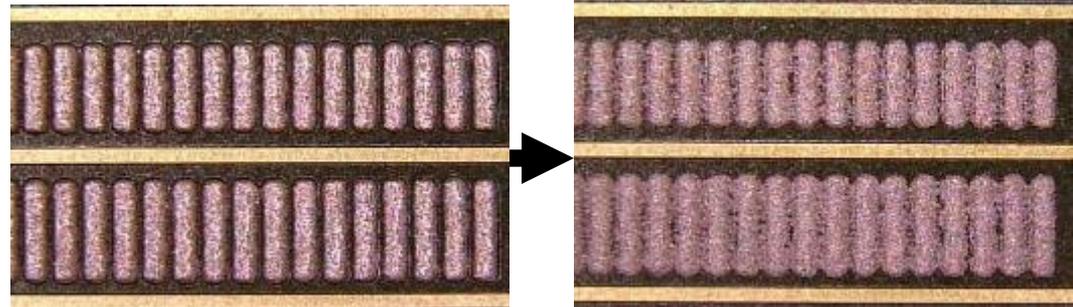
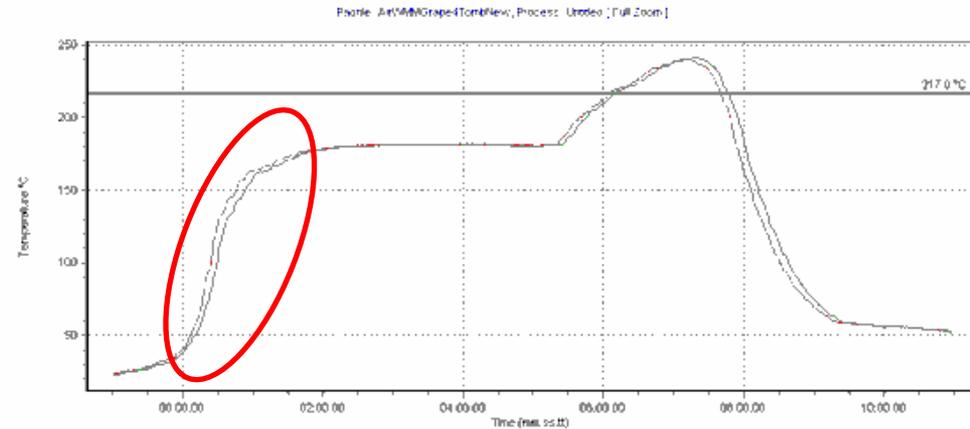


# SMD vs. NSMD Pads



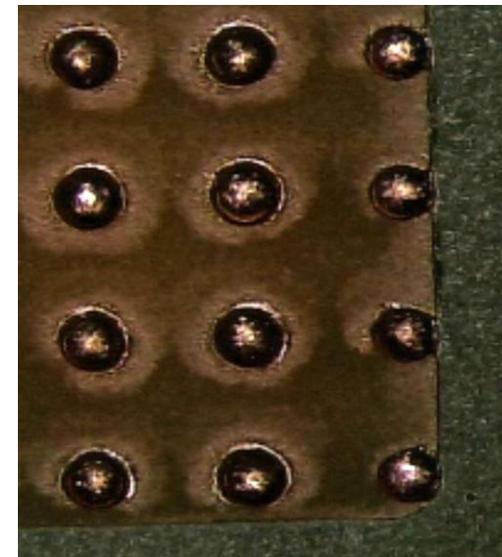
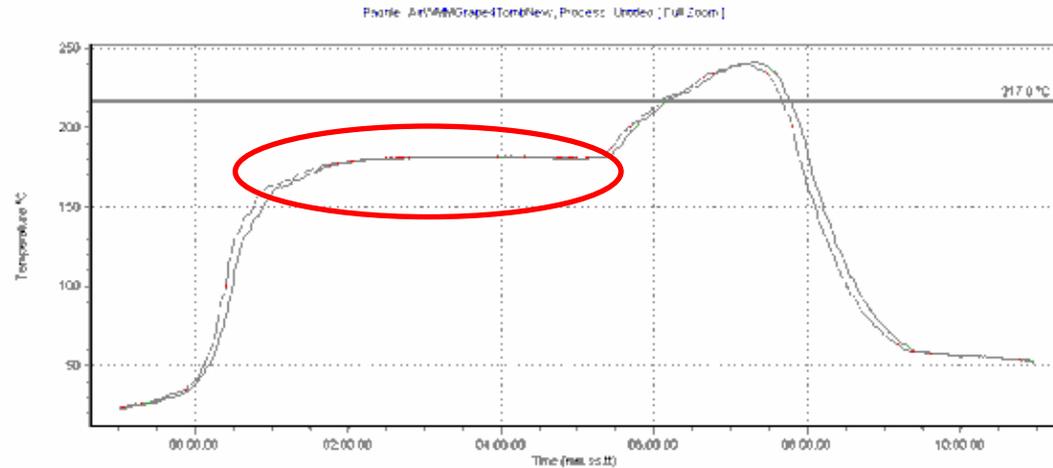
# Investigation: Reflow - Preheat

- Fast ramp rate increases slumping
- Slow ramp rate minimizes spacing between paste and solder ball
- Added Considerations:
  - Metal %
  - Powder size
  - Solvent
  - Print height



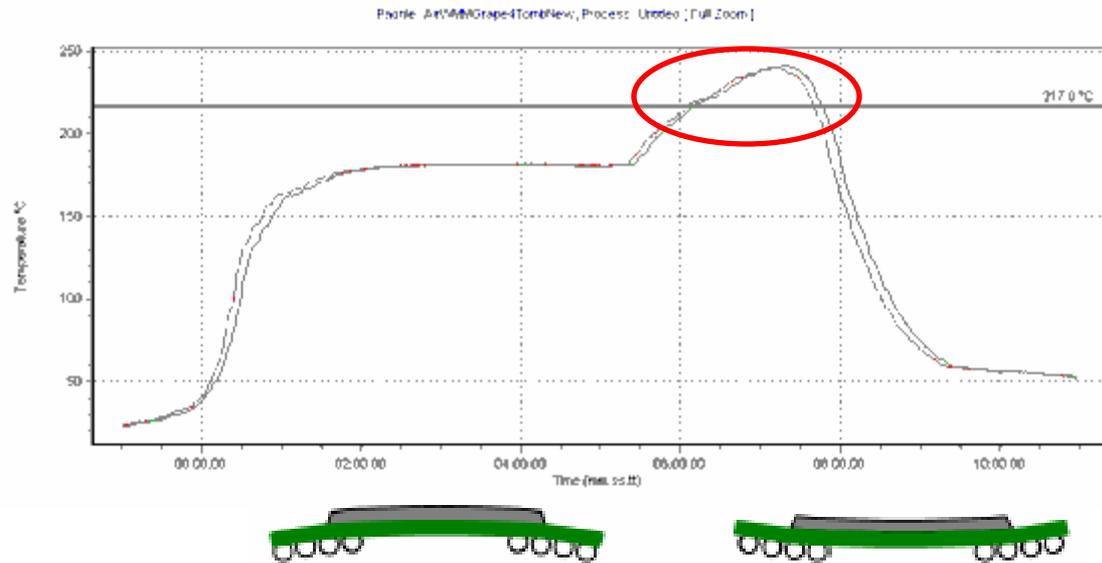
## Investigation: Reflow - Soak

- Oxidation occurs the entire time that the board is in the preheat and soak stages of the profile
- Oxidation barrier of solder paste critical
- Other considerations:
  - Soak profile helps voiding
  - High air flow rates



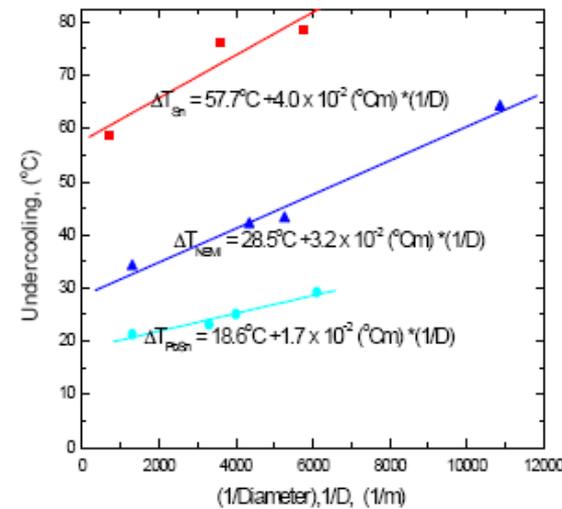
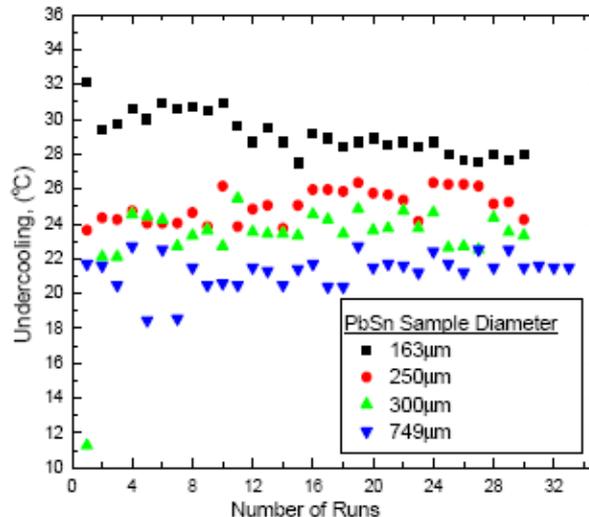
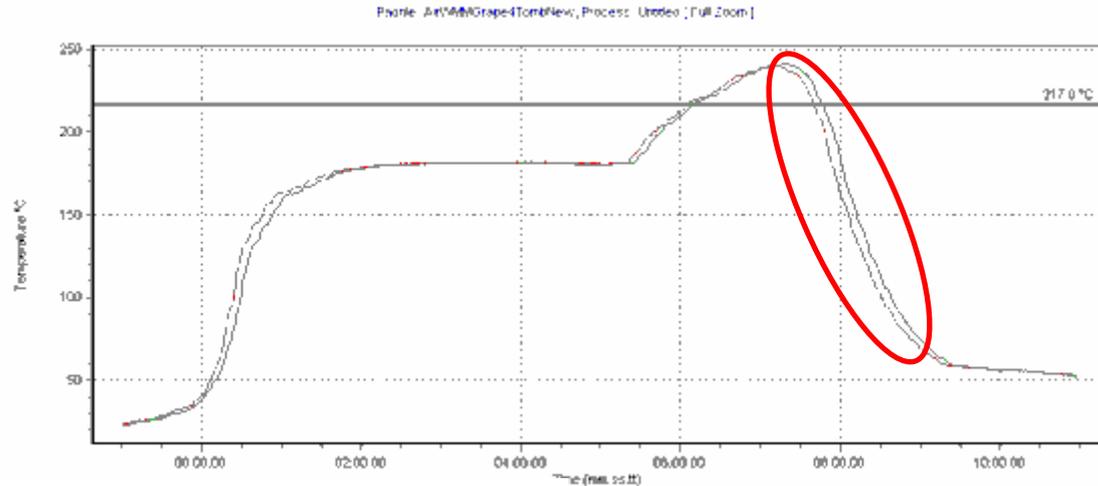
# Investigation: Reflow - Peak

- Peak temperature affects the amount of warping
- TAL impacts the amount of oxides that form on molten solder surface
- Other considerations:
  - Intermetallic formation
  - Low Ag BGA's



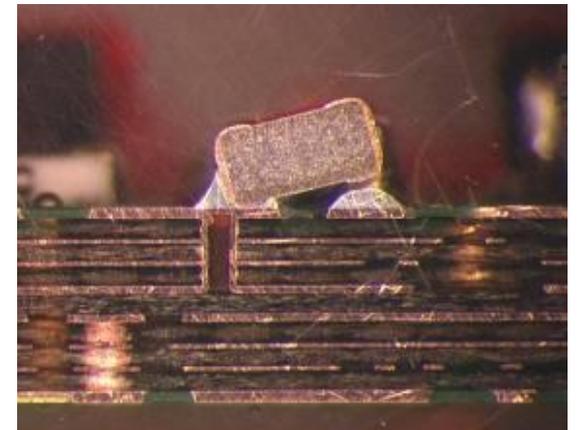
# Investigation: Reflow - Cool Down

- Undercooling a positive attribute for HIP
- Closer to pure Sn the alloy is, the more undercooling
- Smaller balls, more undercooling
- Some confounding info for mixed alloys



Source: Kinyanjui R; *Effect of Ball Size on Undercooling of SAC Solder Joints*; SMTAI 2005

- Nitrogen will improve the solder joint appearance and spread
- Nitrogen will minimize surface oxidation
- There is no evidence that a solder joint reflowed in nitrogen is any more reliable
- Nitrogen will dramatically increase tombstoning of small passive components



# Investigation: Paste - Activators/Halogens

## Halogen-Free

- It does not contain Cl, Br, F, I, At (although most just looking at Cl and Br)
- Concern is Environmental
  - Uncontrolled incineration
  - Dioxin formation
- Some Legislation Emerging
- Common in Flame Retardants
- Issues:
  - Do the halogen free PCB's impact end product reliability?

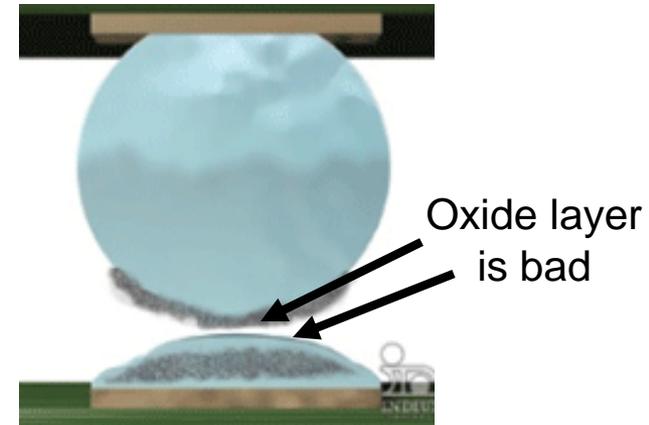
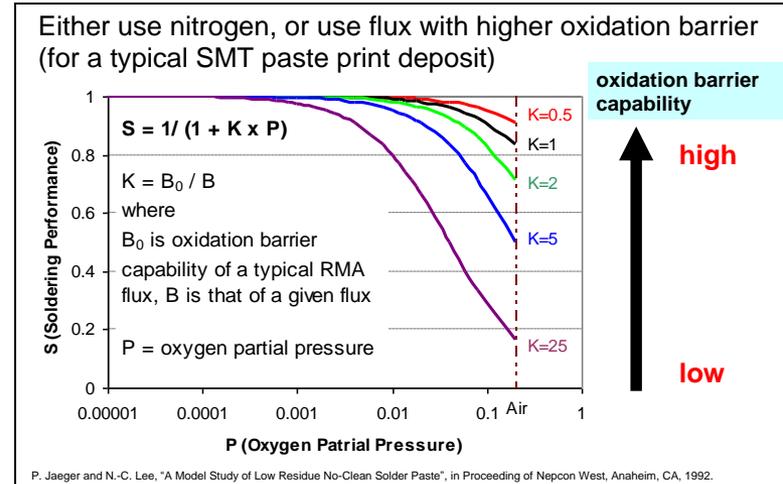
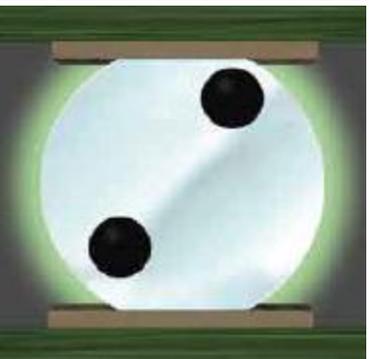
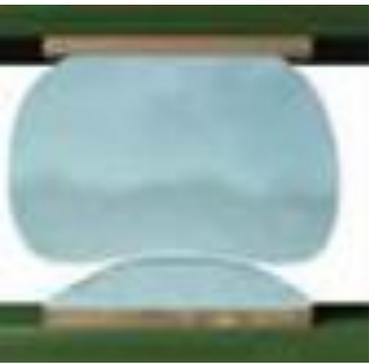
## Halide-Free

- Should be halide ion free as it is defined in electronics as not containing ionic halides.
- Concern is Reliability
  - Corrosion
  - Dendritic Growth
- Common in Activators in flux
- Issues:
  - Is halide free actually more reliable than halide contained?
  - How do you test fluxes for halide content?

# Investigation: Paste - Oxidation Barrier

## Composition of Fluxes

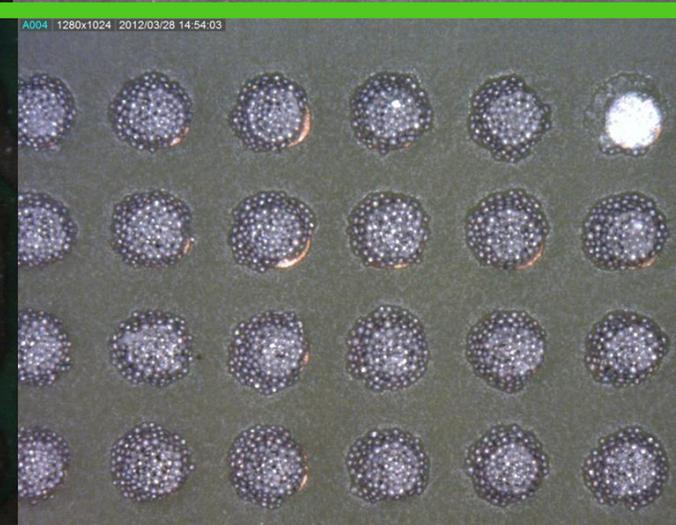
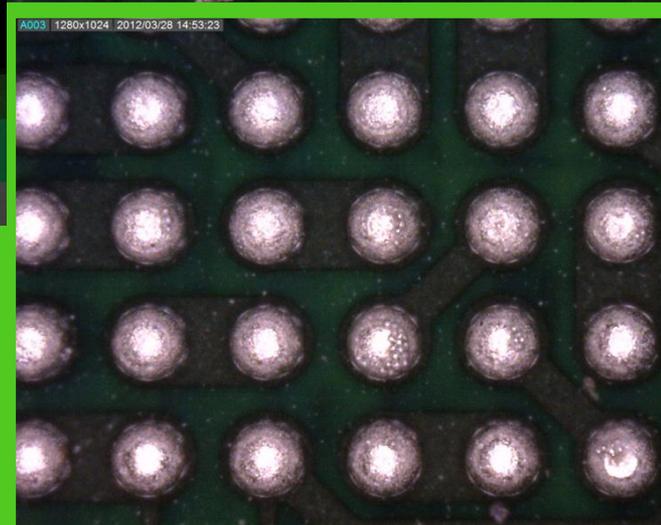
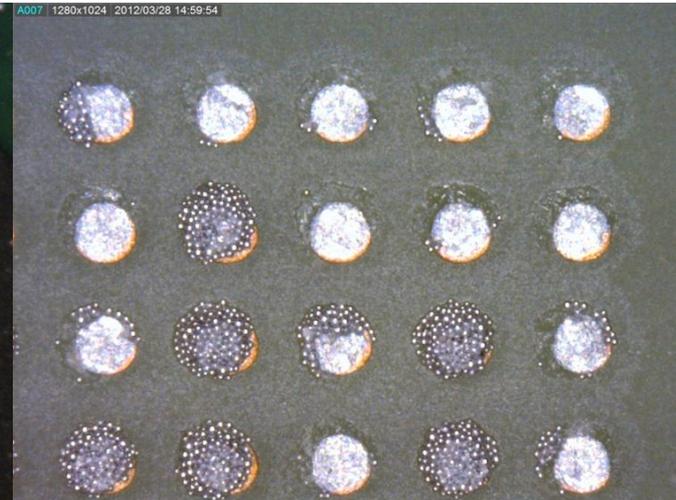
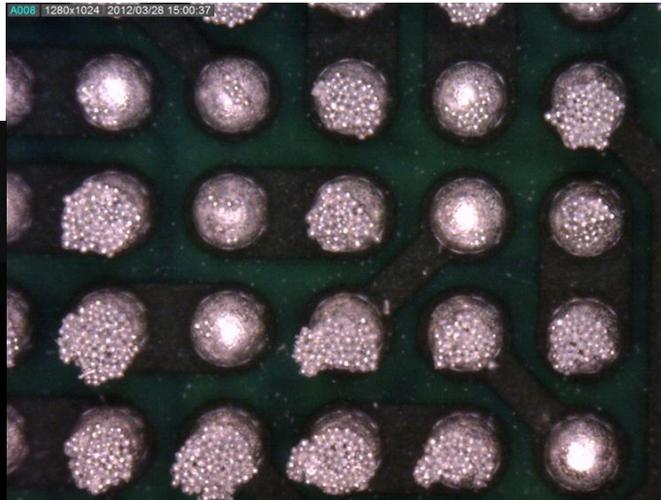
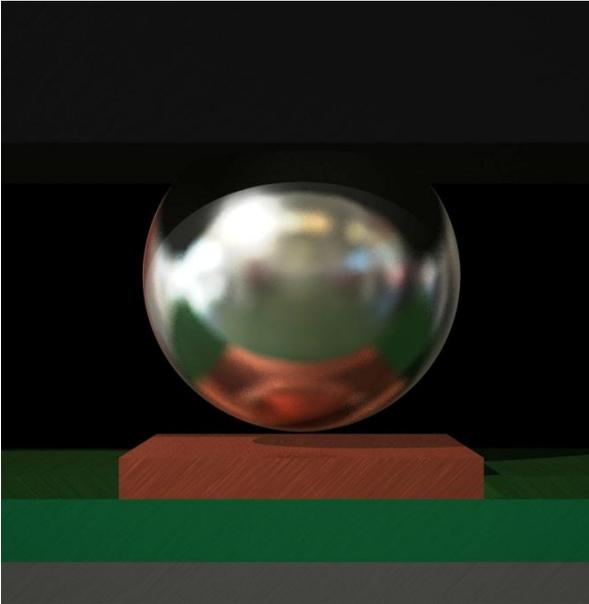
- **Activators**
  - Dissolve oxides off the metal surfaces & promote wetting
  - Halogens or organic acids
- **Resins/Rosins**
  - Tacky and viscous
  - acts as an oxygen barrier
- **Rheological Additives**
  - Create the thixotropic properties of solder paste
  - Key for Stencil Printing
- **Solvents**
  - Dissolves *activators, gelling agents, & resins* to create a homogeneous *paste flux*
  - Key to voiding and stencil life



# Investigation: Paste - Pad Adhesion

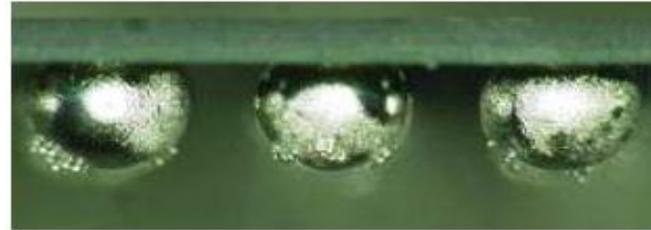
Component

Board

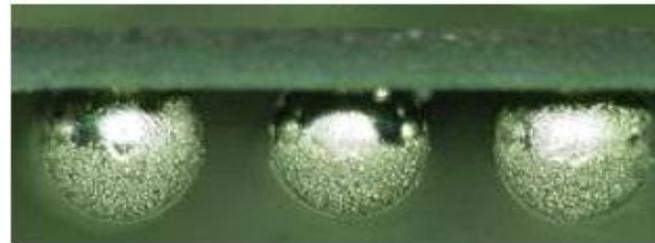


# Investigation: Printing AND Dipping

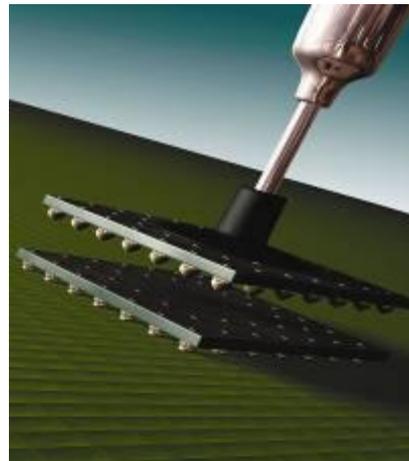
- Flux
  - Adds oxide barrier to sphere
  - Additional activity
- Paste
  - Same as flux, plus...
  - Accommodates more warp



Dipped into normal solder paste

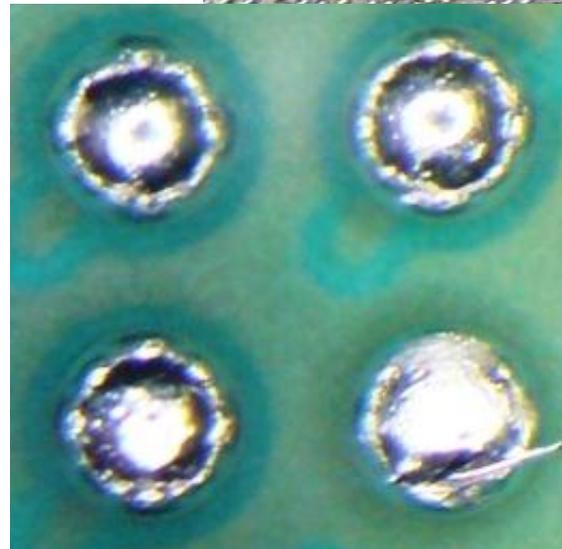
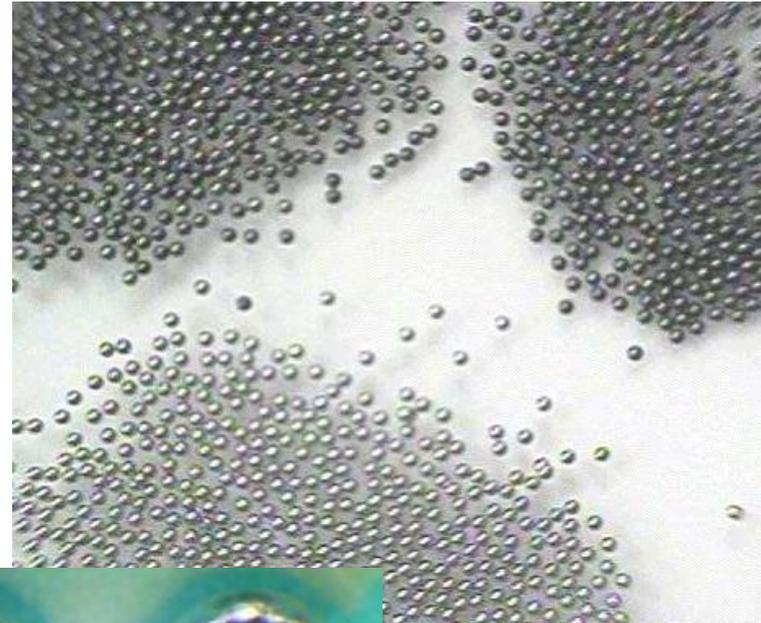


Dipped into PoP solder paste



# Supplier Issues

- Sphere Oxidation
  - Uncontrolled manufacturing
  - Packaging
  - Storage
- Silver Segregation
  - Cases seen as high as 36% silver content at the surface.
  - Silver tailing
- Beyond solder paste control



# Case Study

- Known Paste Solution
  - 93% yield (7% fall-out) current process, current paste
  - 100% yield (no fall out); current process, new paste
  - 300 boards / >1000 IO's per board



- Currently in production
- Work with your solder paste supplier

- Random HIP Defects
  - Look for supplier / storage issues
- Edge / Center HIP Defects
  - Look for process issues (placement / warpage)
- Paste properties can overcome HIP defects
  - Look for high transfer efficiency
  - Look for “stringy” pastes
  - Look for a high oxidation barrier
  - Look for slump resistance
- You are not alone

# HoP Mitigation

